



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10645294</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>TANAKA, TOKIO</p>
	<p>Examiner</p> <p>Layno, Benjamin H</p>	<p>Art Unit</p> <p>3711</p>

Class	SubClass	Date	Examiner
273	308, 292, 302-306	8/5/06	bhl
D21	384, 383, 376		

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Interference Searched 	Application/Control No. 10645294	Applicant(s)/Patent Under Reexamination TANAKA, TOKIO
	Examiner Layno, Benjamin H	Art Unit 3711

Class	SubClass	Date	Examiner
273	250-299, 300-349	8/5/06	bhl

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